

## DETAILED ACTION

### *Response to Arguments*

Applicant's arguments, see Remarks, filed 10/10/2011, with respect to the 35 U.S.C. 112, second paragraph, rejections of claims 1-10 and the 35 U.S.C. 101 rejections of claims 8-10 have been fully considered and are persuasive. The previous grounds of rejection have been withdrawn.

### *Allowable Subject Matter*

Claims 1-10 are allowed.

The following is an examiner's statement of reasons for allowance: The prior art taken either singularly or in combination fails to anticipate or fairly suggest the limitations of the independent claims 1, 4, 7, and 8.

Regarding claim 1, the prior art taken either singularly or in combination fails to anticipate or fairly suggest a device for recording data and data structures on a write-once storage medium, the data structures comprising space bit map and defect management structures, the device comprising writing means for recording the data and the data structures; controlling means for generating the data structures and controlling the writing means; during wherein as the data is recorded, the controlling means are adapted to control the writing means to record the data structures on the write-once storage medium at a predefined temporary location in a reserved area on the write-once storage medium and ***after the data structures are recorded in the temporary location, then the controlling means are adapted to control the writing***

***means to finalize the write-once storage medium by recording the data structures on the write-once storage medium at a predefined fixed location on the write-once storage medium, wherein the predefined fixed location is a location on the write-once storage medium that corresponds to a location that is predefined for a rewritable storage medium, wherein the predefined fixed location is a different location on the write-once storage medium than the predefined temporary location, and wherein the space bit map indicates written and free areas of the write-once storage medium, the defect management structures indicating the locations of rewritten data for respective track defects of the write-once storage medium.***

Regarding claim 4, the prior art taken either singularly or in combination fails to anticipate or fairly suggest a method of recording data and data structures on a write-once storage medium, the data structures comprising space bit map and defect management structures, the method comprising acts of: recording the data on the write-once storage medium; as the data is recorded, recording the data structures on the write-once storage medium at a predefined temporary location in a reserved area on the write-once storage medium, and wherein the space bit map indicates written and free areas of the write-once storage medium, the defect management structures indicating the locations of rewritten data for respective track defects of the write-once storage medium; ***after the data structures are recorded in the temporary location, then finalizing the write-once storage medium by recording the data structures on the write-once storage medium at a predefined fixed location on the write-once***

***storage medium, wherein the predefined fixed location is a location on the write-once storage medium that corresponds to a location that is predefined for a rewritable storage medium, wherein the predefined fixed location is a different location on the write-once storage medium than the predefined temporary location.***

Regarding claim 7, the prior art taken either singularly or in combination fails to anticipate or fairly suggest a write-once storage medium that is finalized, the write-once storage medium comprising data structures including space bit map and defect management structures, wherein as the data is recorded, the data structures are recorded on the write-once storage medium at a predefined temporary location in a reserved area on the write-once storage medium and ***after the data structures are recorded in the temporary location, then the disc is finalized by recording the data structures on the write-once storage medium at a predefined fixed location on the write-once storage medium, wherein the predefined fixed location is a location on the write-once storage medium that corresponds to a location that is predefined for a rewritable storage medium, wherein the predefined fixed location is a different location on the write-once storage medium than the predefined temporary location, and wherein the space bit map indicates written and free areas of the write-once storage medium, the defect management structures indicating the locations of rewritten data for respective track defects of the write-once storage medium.***

Regarding claim 8, the prior art taken either singularly or in combination fails to anticipate or fairly suggest a non-transitory medium comprising a computer program for recording data and data structures on a write-once storage medium, the data structures comprising space bit map and defect management structures, which program when loaded into a memory of a recording device is operative to cause a processor to perform acts of: recording the data; as the data is recorded, recording the data structures on the write-once storage medium at a predefined temporary location in a reserved area on the write-once storage medium; ***after the data structures are recorded in the temporary location, then finalizing the write-once storage medium by recording the data structures on the write-once storage medium at a predefined fixed location on the write-once storage medium, wherein the predefined fixed location is a location on the write-once storage medium that corresponds to a location that is predefined for a rewritable storage medium, wherein the predefined fixed location is a different location on the write-once storage medium than the predefined temporary location, and wherein the space bit map indicates written and free areas of the write-once storage medium, the defect management structures indicating the locations of rewritten data for respective track defects of the write-once storage medium.***

Dependent claims 2-3, 5-6, and 9-10 are allowed with their respective base claims.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably

accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

### ***Conclusion***

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Kim et al. (US 6,922,802) discloses a method for creating defect management information. Ko et al. (US 6,804,797) discloses a method of verifying defect management. Shin (US 6,529,458) discloses a recording medium. Mine et al. (US 5,978,336) discloses an optical disk finalization method. Ijtsma et al. (US 6,594,209) discloses recording method. Ijtsma et al. (US 6,606,285) discloses a recording method.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to THOMAS ALUNKAL whose telephone number is (571)270-1127. The examiner can normally be reached on M-F 7:30-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wayne Young can be reached on (571)272-7582. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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